# **ACP-1104**

# **Environment Test Report**

Report NO: 15P020007

	<b>▼</b> Pass
Summary	□ Fail
	Pass with Deviation
	Comment:

Issue date	Approval	Test Engineer
2015-03-27	KJ Wang	Rex / Juno

# **Test item list**

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### **Testing Result**

Num	Test item list	Result	Remark
1	High Temperature Operation test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

# **Configuration of EUT**

Num	Item	Spec
1	CPU	Intel Celeron J1900 1.99GHz)
2	CPU Board	BOXER-6403
3	BIOS	(C1A4AM10)
4	Memory	DSL DDR3L 1600 2GB CL11 (SEC-431-BYK0-K4B2G0846Q)
5	mSATA	Toshiba 64GB
6	Test Software	Windows 7 / Run PassMark Burn In Test 8.0 Pro

### System Picture





**Test Date:** 02-26~27-2015

Test Product: ACP-1104

Test Site: AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-2 Testing procedures

Test Bd: Dry Heat Test (Operation)

### **Test Equipment:**

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)

Model: THS-D7S-100+1 N2 Date of Calibration: 10/09/'14

Serial Number: 3898

### **Temperature Measurement:**

40 Channel Thermal Recorder:

YOKOGAWA Inc,

Model: DA100-13-1D

Date of Calibration: 11/09/2014 Serial Number: 12A32319

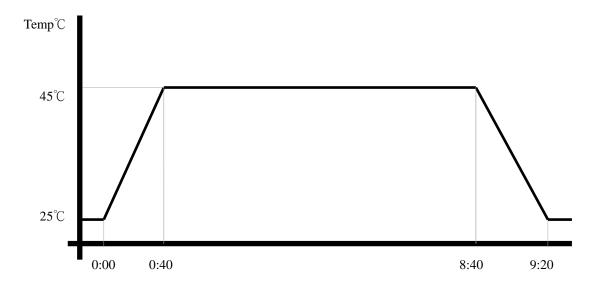
### **Testing Item:**

1. Test Temperature: 45°C

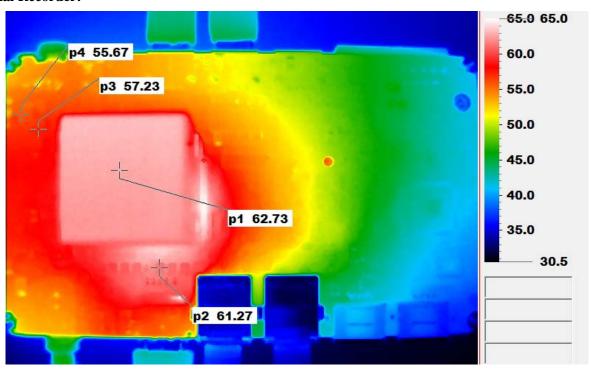
2. Test Times: 8Hrs

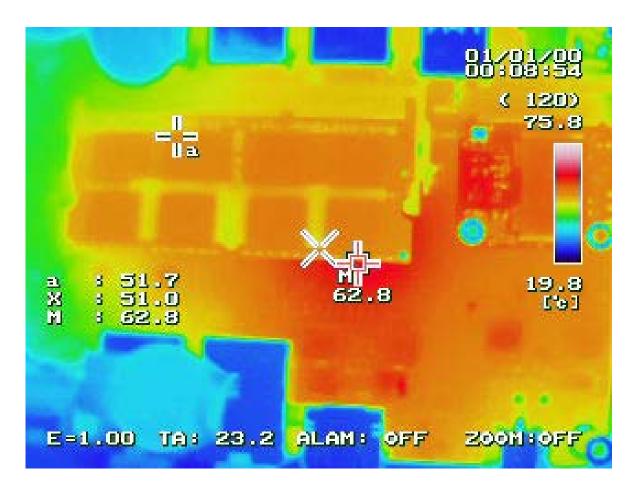
3. Test Software: Windows 7 / Run PassMark Burn In Test 8.0 Pro

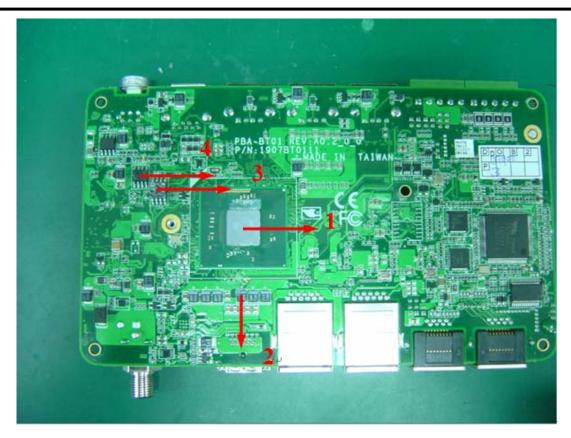
4. Test Environment Curve:

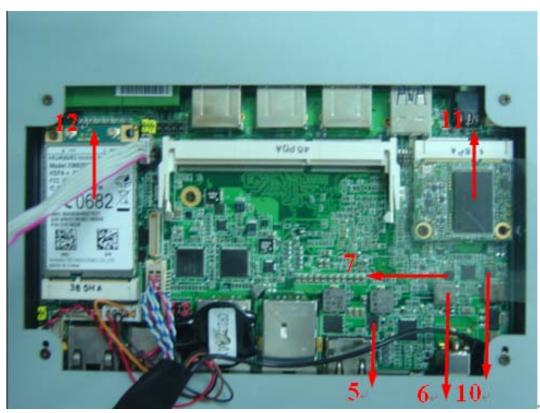


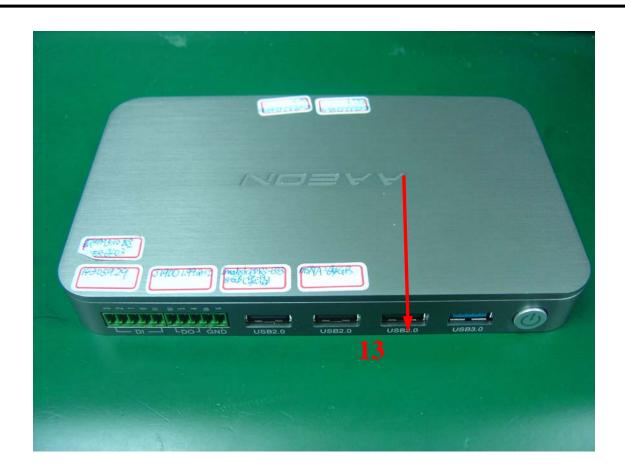
### **Terminal Recorder:**











### ACP-1104 (With 0.5m/sec airflow)

Thermal profile data:

<u>Point</u>	Location	Describe	Tc (*1) (°C)	Tm (*2) Measured Under 45℃	Note
1	U50	Intel® Celeron™ J1900 1.99GHz	105	70.1	
2	C467	(TF)CAP.330uF.2.5V.20%.B2(3.5*2.8*1.9mm).SMD.9mohm.NEC-T OKIN.TEPSGB20E337M9-8R	105	73.2	
3	U45	(TF)IC.64 Mbit SPI Flash SOIC-8P 208mil.SMD Winbond W25Q64FVSSIG	85	70.4	
4	U41	(TF)IC.LDO Linear Regulator 0.23V 2A.SOP-8(Exposed Pad) SMD RICHTEK.RT9025-25PSP	120	71.8	
5	U24	TF)IC.Synchronous Buck NexFETTM.SON 8P.Power Stage SMD TI CSD97374Q4M	150	74.8	
6	L7	3.3UH	150	83.5	
7	Q15	FDMC7200S	150	80.0	
8	BAT 1	RTC Battery	85	59.4	
9	DIMM12	DIMM	85	77.1	
10	Q14	FDMC7200S	150	75.9	
11		Ta (under mSATA)	N/A	77.2	
12		Ta (under 3G module)	N/A	73.6	
13		Control Box External Surface Temperature	N/A	51.2	

#### Note(\*):

- 1. "Tc" indicates the component's case maximum temperature value specified in its datasheet.
- 2. "Tm" indicates the measured Tc value under working environmental temperature within product specification.
- 3. Judgment Criteria:
  - Fail : Tm > Tc; The measured value is over specification.
  - Margin Pass:  $Tc > Tm > Tc-5^{\circ}C$ ; The measured value is within specification with margin.
    - It is strongly recommended to add thermal dissipation design for better reliability.
  - Pass : Tm < Tc-5%; The measured value is with safety margin.

#### **Sample Configuration & Quantity Under Test:**

Quantity: 1 (ACP-1104)

#### **Test Result:**

No issues were found during the temperature rise operation test.

### Temperature cycle test

**Test Date:** 03-24 ~ 26-2015

**Test Product :** ACP-1104

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC68-2-14 Testing procedures

Test N: Change of temperature Test

**Test Equipment:** 

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)

Model: THS-B6T-150+LN2 Date of Calibration: 09/01/14 Serial Number: 9095KT

**Test Condition:** 

1. Test Low Temperature:  $0^{\circ}$ C (1~3 cycles)

-5°C (4<sup>th</sup> cycle)

2. Test High Temperature:  $45^{\circ}$ C (1~3 cycles)

 $50^{\circ}$ C (4<sup>th</sup> cycle)

3. Test dwell time: 6Hrs

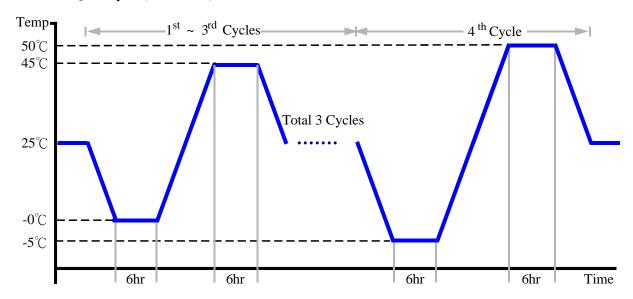
4. Temperature slope: 2°C/min

5. Test cycle: 4 cycles

6. Test Environment Curve:

#### **Sample Configuration & Quantity Under Test:**

Quantity: 1 (ACP-1104)



### **Test Result:**

No issues were found during the temperature operation cycle test.

### **High temperature storage test**

**Test Date:** 03-22 ~ 24-2015

**Test Product:** ACP-1104

Test Site: AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-2 Testing procedures

Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:** 

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)

Model: THS-B6T-150+LN2 Date of Calibration: 09/01/14 Serial Number: 9095KT

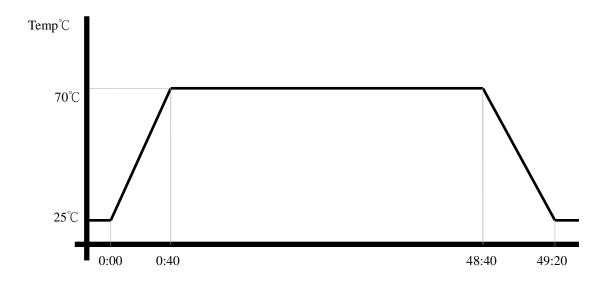
**Testing Item:** 

5. Test Temperature: 70°C

6. Test Times: 48Hrs

7. Test Software: Windows 7 / Run PassMark Burn In Test 8.0

8. Test Environment Curve:



### Sample Configuration & Quantity Under Test:

Quantity: 1 (ACP-1104)

#### **Test Result:**

No issues were found after the high temperature storage test.

### Low temperature storage test

**Test Date:** 03-20 ~ 22-2015

**Test Product:** ACP-1104

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-1 Testing procedures

Test Ab: Cold Test (Non-operation)

**Test Equipment:** 

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)

Model: THS-B6T-150+LN2 Date of Calibration: 09/01/14 Serial Number: 9095KT

**Testing Item:** 

1. Test Temperature: -20°C

2. Test Times: 48Hrs

3. Test Software: Windows 7 / Run PassMark Burn In Test 8.0

4. Test Environment Curve:



### **Sample Configuration & Quantity Under Test:**

Quantity: 1 (ACP-1104)

#### **Test Result:**

No issues were found after the low temperature storage test.

### **Humidity test**

Test Date: 03-18~20-2015

**Test Product:** ACP-1104

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-3 Testing procedures

Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:** 

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)

Model: THS-B6T-150+LN2 Date of Calibration: 09/01/14 Serial Number: 9095KT

**Testing Item:** 

1. Test Temperature: 40°C

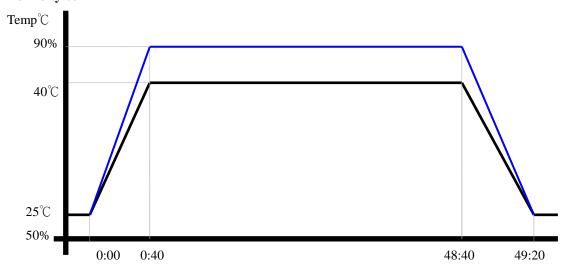
2. Test Humidity: 90%RH

3. Test Times: 48Hrs

4. Test Software: Windows 7 / Run PassMark Burn In Test 8.0

5. Test Environment Curve:

#### **Humidity %**



### **Sample Configuration & Quantity Under Test:**

Quantity: 1 (ACP-1104)

#### **Test Result:**

No issues were found after the humidity storage test.

### Cold start and hot start test

**Test Date:** 03-17~18-2015

**Test Product:** ACP-1104

Test Site: AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-14 Testing procedures

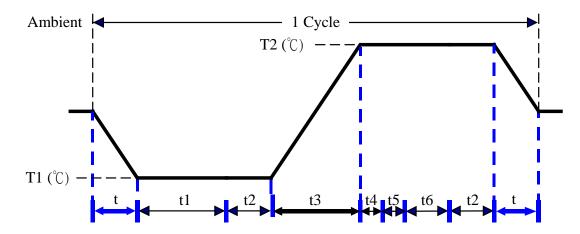
Test N: Change of temperature Test

**Test Equipment:** 

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)

Model: THS-B6T-150+LN2 Date of Calibration: 09/01/14 Serial Number: 9095KT

#### **Test Condition:**



Parameters	Description
T1	-5°C
T2	50°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope

t, t1, t6: Power Off

t2: Power on/off test 10 times (on 2 min / off 5min)

t3, t4: Run burn in test 8.0

t5: Win 7 Software restart test 3 times

Test Software: Windows 8.1

### **Test Result:**

a. No issues were found during the cold start test.

b. No issues were found during the hot start test.